

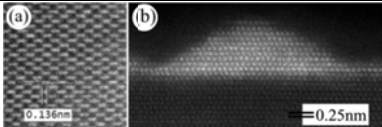


Characterisation <b>HRTEM TITAN</b> CEA-LITEN, France							
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<b>Material class:</b>	Silicon X	Polymer	Metal X	Ceramic X	Glass X	Organic	Other
<b>Short technology description:</b>	The Titan transmission electron microscope of FEI operates at 300kV. It is equipped with a Cs-probe corrector for high resolution scanning transmission electron microscopy (HRSTEM) at Angstrom scale, and with EDS and GIF detectors for chemical analysis.						
<b>Typical structures and designs:</b>			<b>FEI Titan TEM @ Minatec</b>				
			<b>GaN quantum dots in STEM mode</b> <b>(JL Rouvière, CEA)</b>				
<b>Special features:</b>	<ul style="list-style-type: none"> <li>- Need a TEM sample (thin area &lt;100nm and diameter of sample &lt;3mm)</li> <li>- The preparation can be done by classical polishing, tripod, ion milling, FIB etc.</li> </ul>						
<b>Limitations, constraints:</b>	<ul style="list-style-type: none"> <li>- Crystalline areas</li> <li>- Good/Perfect sample preparation (thin without defect).</li> </ul>						
<b>Material examples:</b>	<ul style="list-style-type: none"> <li>- Si nanowires, Pt catalysts, carbon nanotubes, quantum dots etc.</li> </ul>						